

JPW



In the United States Patent and Trademark Office

Re the application of
Lee D. Whetsel
Serial No.: 10/806,539
Filed: March 23, 2004
Title: Probeless Testing of Pad Buffers on Wafer

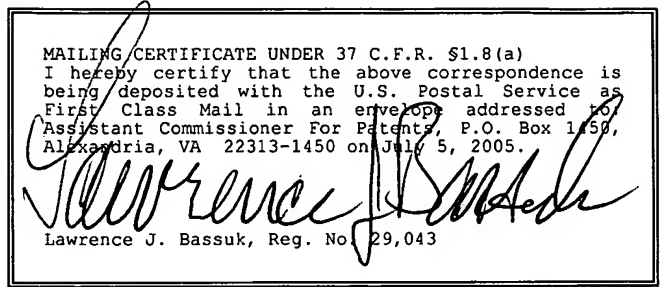
TI-25300.2
Art Unit: 2133
Examiner: TBD

Resubmitted Preliminary Amendment B Under 37 CFR 1.111

July 5, 2005

Asst. Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Dear Sir:



Before examination; please amend the above-mentioned application as follows: